

STATUS 5

**A Reliability Assessment Tool For
NDT Inspection Systems**





STATUS 5 Overview

Introduction – Advantages



ES

STATUS 5



Introduction

- STATUS 5 is a convenient NDT tool for assessing the efficiency and reliability of NDT techniques and evaluating operator performance.
- The software generates Probability of Detection (POD) curves for all NDE systems, based on statistical analysis of data imported by the user.
- STATUS 5's Sizing Accuracy study assists the user's NDT technique by comparing actual flaw sizes, reported after destructive testing, to the user's flaw sizing capability.
- The Sizing Optimization tool provides guidance to optimize calibration curves implemented from the acquisition system and increase the sizing accuracy based on your specifications.



ES STATUS 5



Major Advantages

- User-friendly interface with a highly visualized presentation.
- Facilitates quick importing/exporting of Excel documents or manual data entry.
- Fast and intuitive to use with extensive help and guidance, tailored for operators with a minimal mathematical background and statistical knowledge.
- Five statistical models available for POD curve generation, including an automated model recommendation based on the most efficient POD curve using the operators imported data.
- Noise Study and Threshold Optimization tools efficiently adjust POD model inputs based on inspection system properties.



STATUS 5 Study List

Probability of Detection – Sizing Accuracy
Sizing Optimization – Noise Study



ES STATUS 5



Main Screen

- Data View, Chart View and Split View available.
- Inspection Data and Actual Test Data columns show defect's length, depth and height.
- Data filtering capability.
- Defect's ID, side, zone and type information shown in columns.
- Recommendation tab and study list.

The screenshot displays the ES STATUS 5 software interface. The main window is titled "ES STATUS - C:\Users\mmarvasti\Desktop\Eclipse\STATUS 5 Development\Full Data Set.Status". The interface includes a menu bar (File, Edit, Tools), a toolbar, and a "Recommend Model" button. The main area is divided into several sections:

- General Parameters:** Includes controls for Measure (Percentage, Amplitude), MeasureType (Length, Height, Depth), Threshold (40%), Saturation (100%), and Confidence (95%). There is a checkbox for "Show Charts Descriptions" and a "Select Processor" dropdown.
- Inspection Data Table:** A table with columns for ID, Amplitude, Position, Length, Depth, Height, and Position. The first row is highlighted in blue.
- Actual Test Data Table:** A table with columns for Length, Depth, Height, Side, Zone, and Type. The first row is highlighted in yellow.
- Control Panels:** Three panels for "Nordtest", "POD", and "Sizing". Each panel has a "Hit / Miss" section with "Logit" and "Probit" buttons, and a "LogLog" and "cLogLog" button. The "Sizing" panel has buttons for "Sizing Accuracy", "Sizing Optimization", and "Noise Study".
- Welcome Message:** A message at the bottom says "Welcome to STATUS 5! Please select your desired study from the Select Study list."

ID	Amplitude	Position	Length	Depth	Height	Position	Length	Depth	Height	Side	Zone	Type
1 J01-2	68	306	7	16.9	1.2	310	0	17.8	1.3	US	HP	LOF
2 J01-4	45	520	22	3	1.2	527	0	3	1.3	DS	F5	LOF
3 J01-5	115	881	13	7.8	3.5	888	0	7.1	2.4	DS	F3	LOF
4 J01-6	64	932	27	7.2	2	939	0	5.9	1.5	US	F3	LOF
5 J01-7	65	994	22	4.4	1.9	1007	0	3.9	0.3	US	F4	LOF
6 J01-8	38	1153	9	3.5	1.3	1158	0	4.1	1.4	US	F4U	LOF
7 J01-9	72	1428	10	10.9	2.5	1433	0	9.2	1.6	DS	F2	LOF
8 J01-10	68	1468	19	4.5	2.2	1473	0	4.3	1.6	US	F4	LOF
9 J01-11	88	1542	76	10.9	2.5	1551	0	10.4	2.3	US	F2	LOF
10 J01-12	63	1631	86	11.9	1.7	1714	0	11.7	0.9	US	F1	LOF
11 J02-1	138	164	57	11.6	2.5	174	50	10.9	2.1	US	F2	LOF
12 J02-2	40	285	34	19.1	0.5	295	0	19.1	0.3	US/DS	RM2	CON
13 J02-3	170	319	11	19.1	1.9	325	0	19.1	1.7	US/DS	Root 2	LOF
14 J02-4A	106	398	75	17.01	2	449	0	17.1	1.3	US/DS	HP	LOF
15 J02-4B	90	398	75	19.1	1.1	449	0	19.1	1.2	US/DS	Root 1	LOF
16 J02-5	62	660	45	19.1	1	698	0	19.1	1.2	US	Root 2	LOF



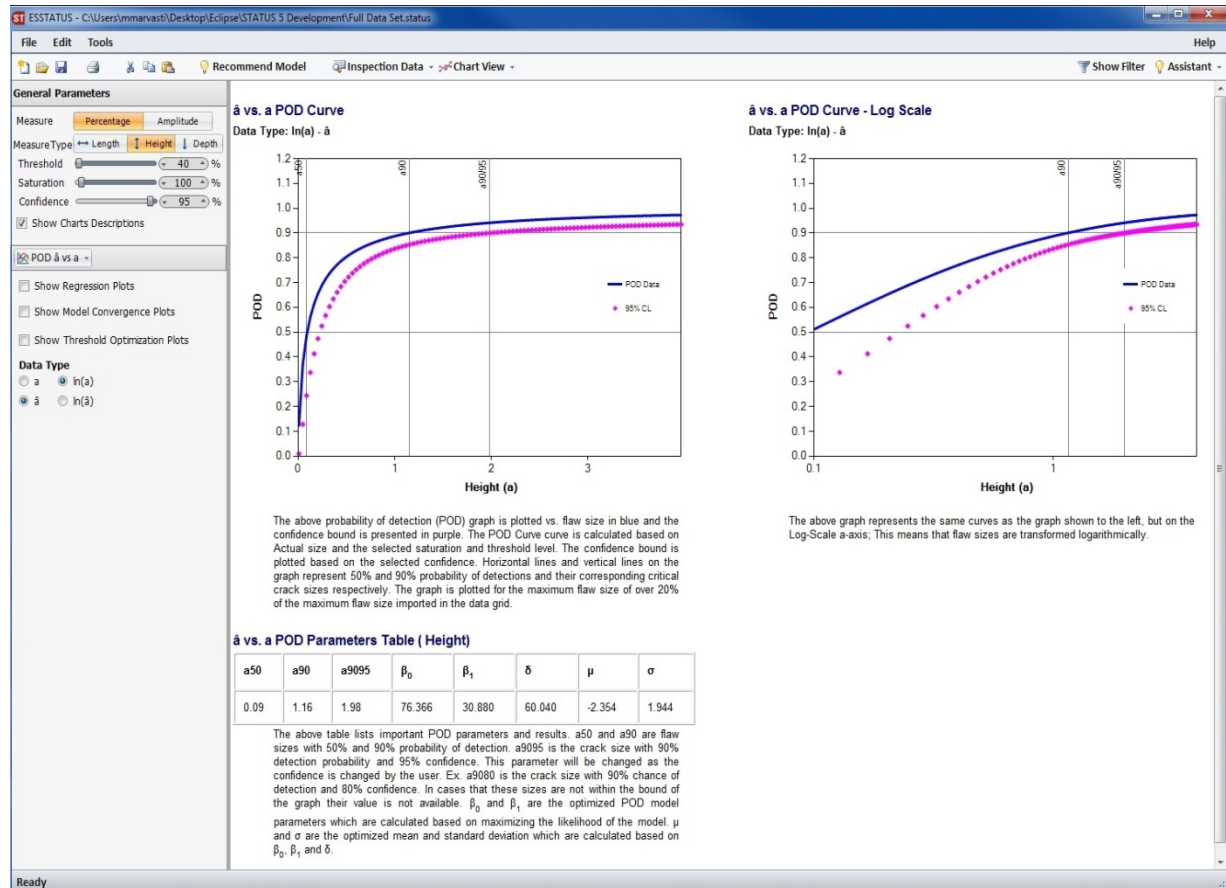
Probability of Detection (POD)

\hat{a} vs. a , Logit, Probit, LogLog, CLogLog
Models



\hat{a} vs. a POD

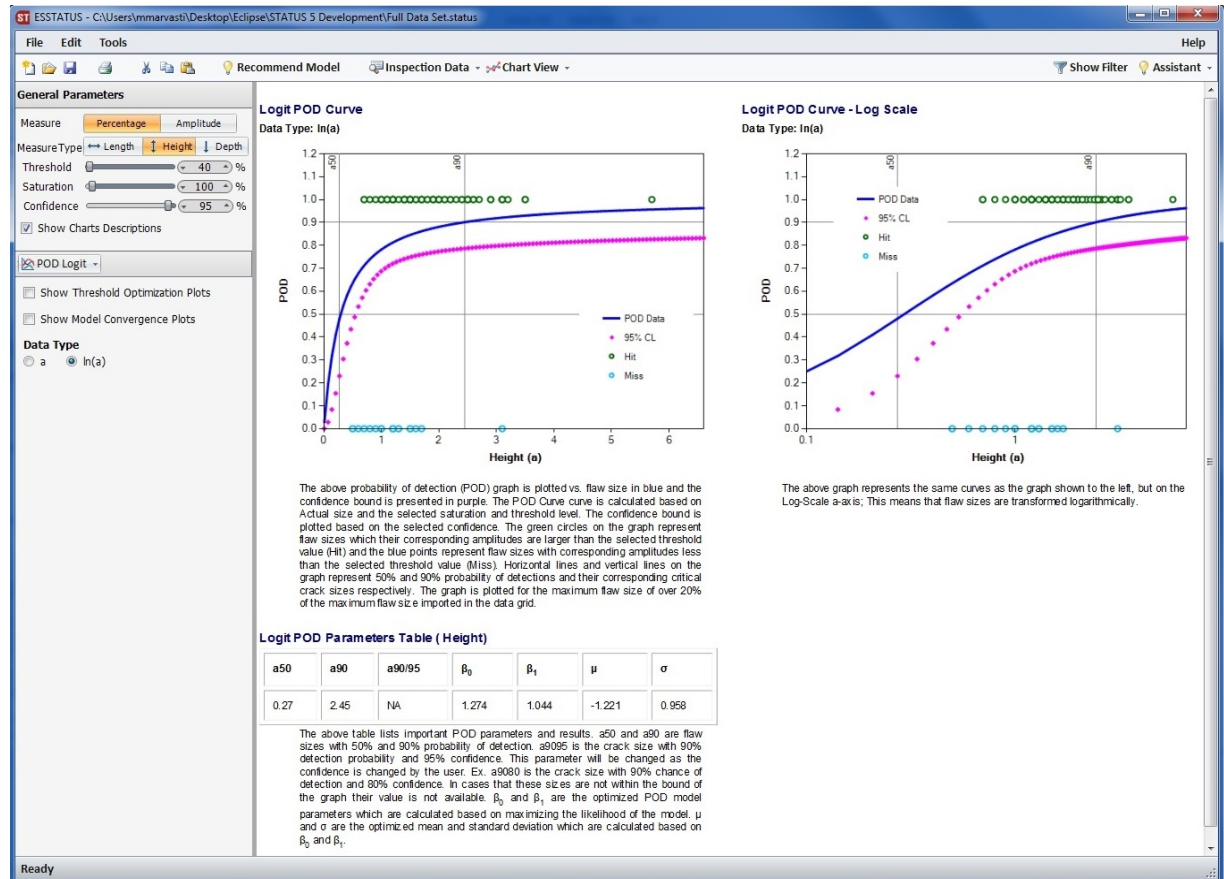
- Defects sizes and amplitudes used with regard to threshold and saturation amplitudes.
- Separate POD curves can be generated based on defects length, height and depth.
- POD and confidence curves available on both Cartesian and log-scale plots.
- Critical defect sizes are specified on the graphs by vertical lines and listed in a summary table.





Hit/Miss PODs

- POD curves are generated based on Hit (1, green points) and Miss (0, blue points) data.
- Separate POD curves can be generated based on the defect's length, height and depth.
- POD and confidence curves available on both Cartesian and log-scale plots.
- Critical defect sizes are graphed by vertical lines and listed in a summary table.





POD Model Recommendation

- Instant analysis and comparison of all 5 models utilized in 12 settings.
- Automatically recommends the most efficient POD model based on AIC values.
- Data fit quality to all POD models is evaluated using BIC values.
- The user is directed to the recommended model with optimized parameters at the click of a button.

POD Model Recommendation

Recommend model processes and analyses all available models and recommends the best fit based on Lowest AIC values. Lower AIC values represent a better fit.

\hat{a} vs. a		AIC	BIC	BIC FIT
\hat{a}	a	696.89	704.85	Very Strong
\hat{a}	ln(a)	696.44	704.40	Very Strong
ln(\hat{a})	a	240.21	248.17	Very Strong
ln(\hat{a})	ln(a)	239.54	247.51	Very Strong
Logit		AIC	BIC	BIC FIT
a		106.82	112.13	Very Strong
ln(a)		105.11	110.42	Very Strong
Probit		AIC	BIC	BIC FIT
a		106.96	112.27	Very Strong
ln(a)		105.27	110.58	Very Strong
LogLog		AIC	BIC	BIC FIT
a		106.67	111.98	Very Strong
ln(a)		104.89	110.20	Very Strong
CLogLog		AIC	BIC	BIC FIT
a		107.15	112.46	Very Strong
ln(a)		105.57	110.87	Very Strong

LogLog Model with Parameter ln(a) is recommended as it has the lowest AIC value.

Go To LogLog Model Close



Probability of Detection (POD)

Nordtest

Imported Data Binning Algorithm Available
for All POD Models



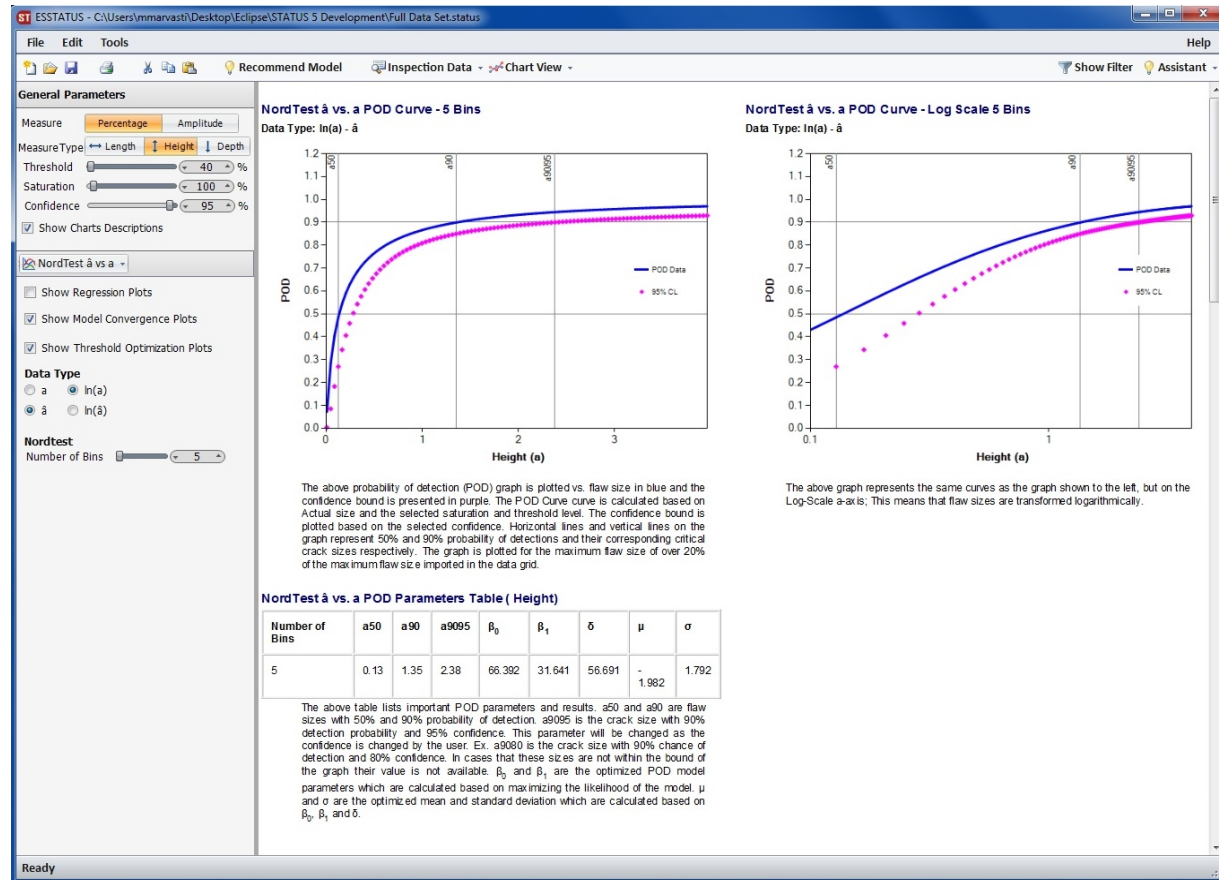
Nordtest \hat{a} vs. a POD

- Imported data can be grouped in the selected number of bins for POD curve generation.

- 5 to 15 bins can be selected by the user.

- POD and confidence curves available on both Cartesian and log-scale plots.

- Critical defect sizes are specified on the graphs by vertical lines and listed in a summary table.





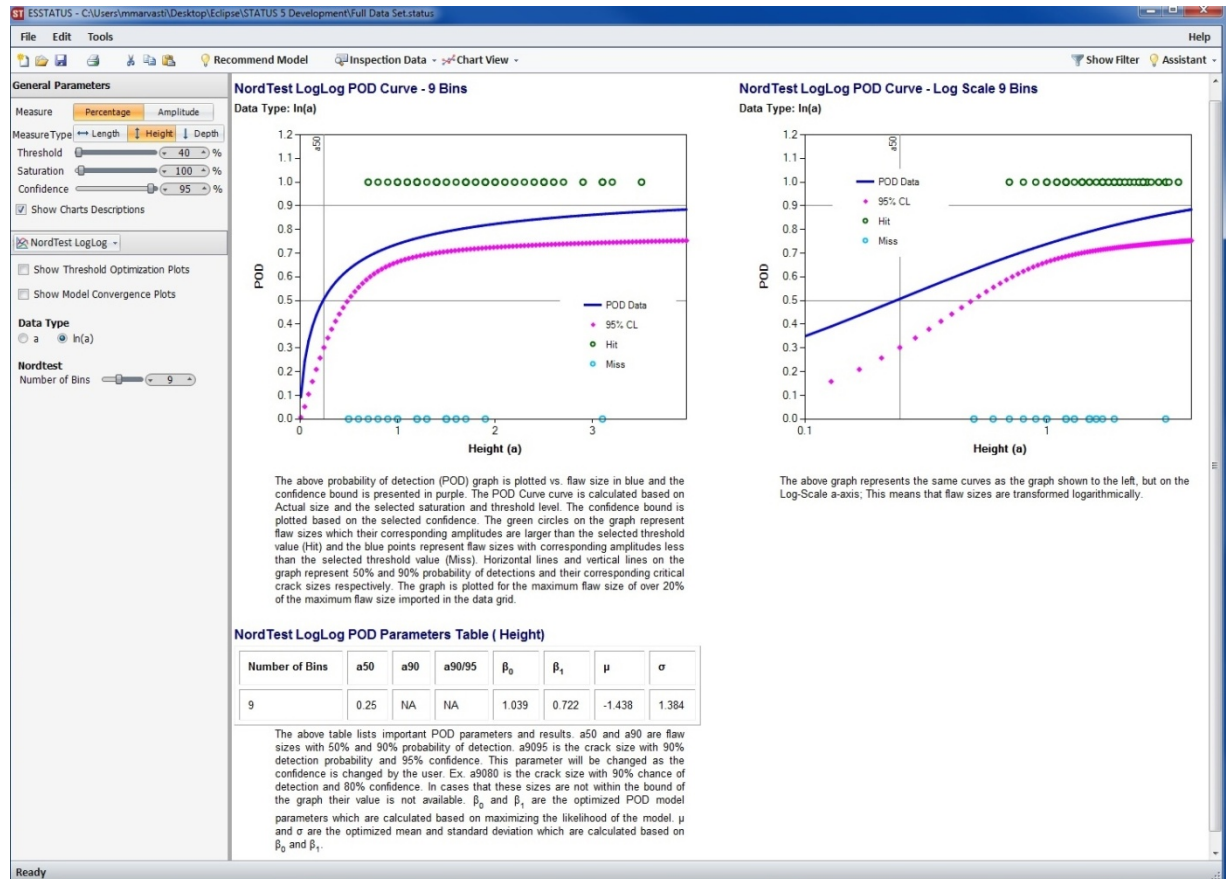
Nordtest Hit/Miss POD

- Imported data can be grouped in the selected number of bins for POD curve generation.

- 5 to 15 bins can be selected by the user.

- POD and confidence curves available on both Cartesian and log-scale plots.

- Critical defect sizes are specified on the graphs by vertical lines and listed in a summary table.





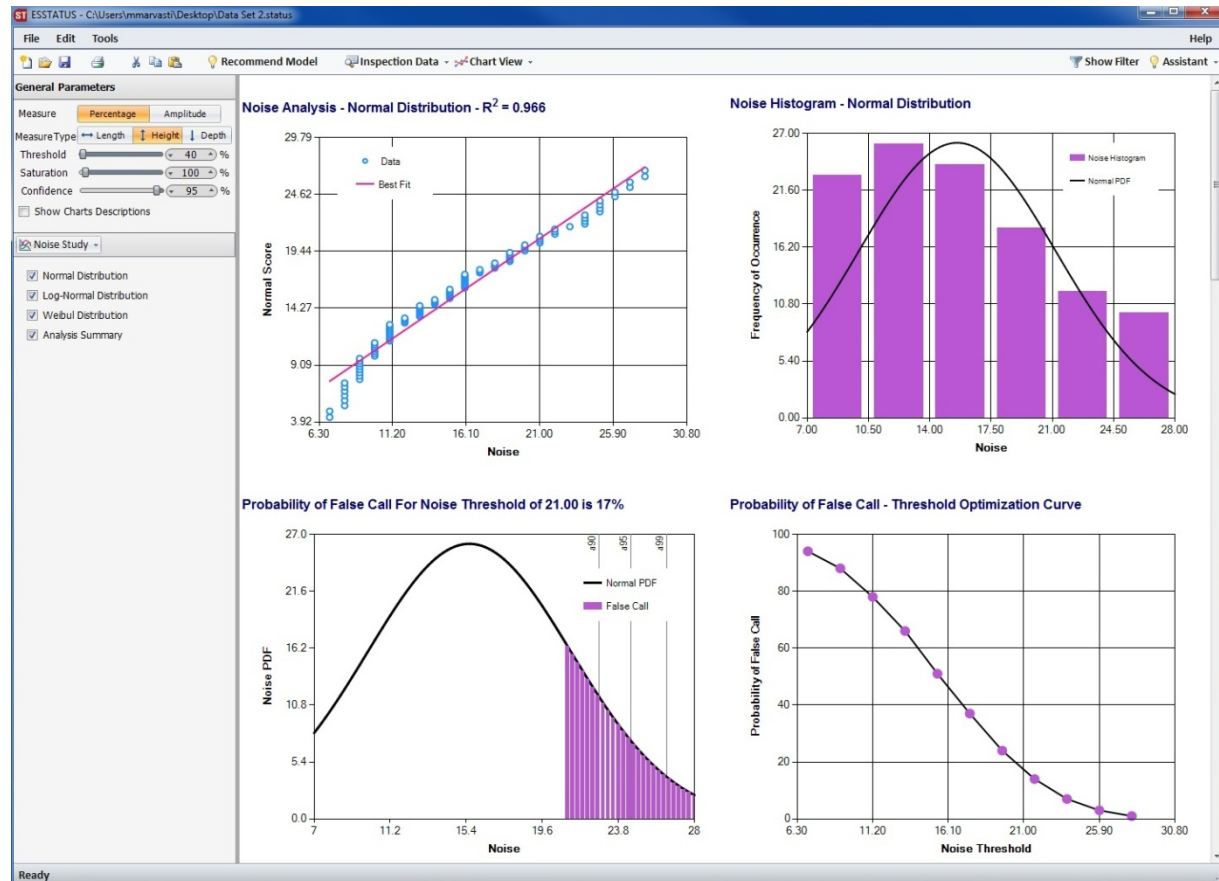
POD Optimization Tools

Noise Study – Threshold Optimization Tool



Noise Study

- An instrument's noise data can be imported to the software.
- Noise statistical distribution is obtained as compared to normal, weibull and log normal distributions.
- Probability of False Call is calculated for different values of threshold based on the noise statistical distribution.
- Critical defect sizes are specified on the graphs by vertical lines.



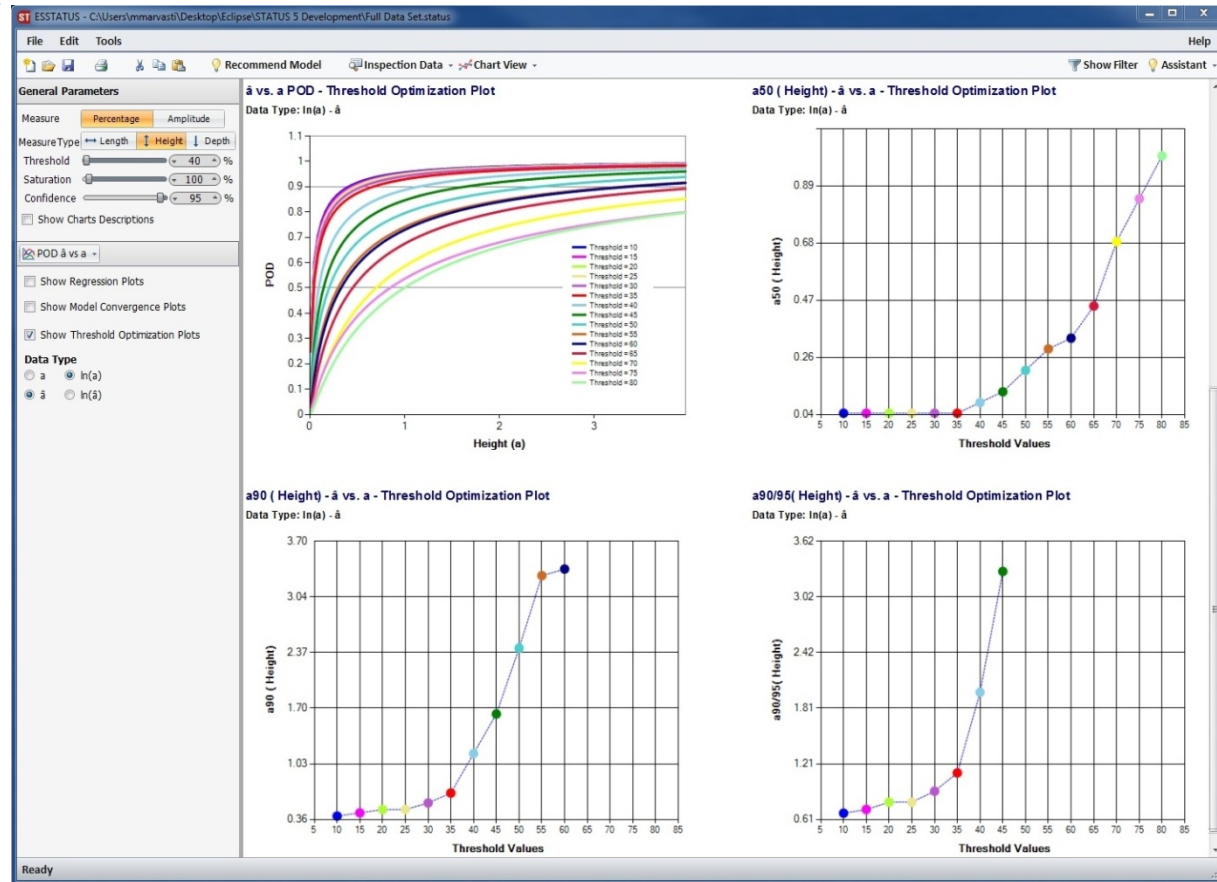


Threshold Optimization

- Effect of threshold value on the shape of the POD curves can be analyzed graphically.

- Various colours can be used to plot POD curves generated by different thresholds, providing a clear comparison on the same graph.

- Effect of threshold values on the values of critical flaw sizes are analyzed in separate graphs.





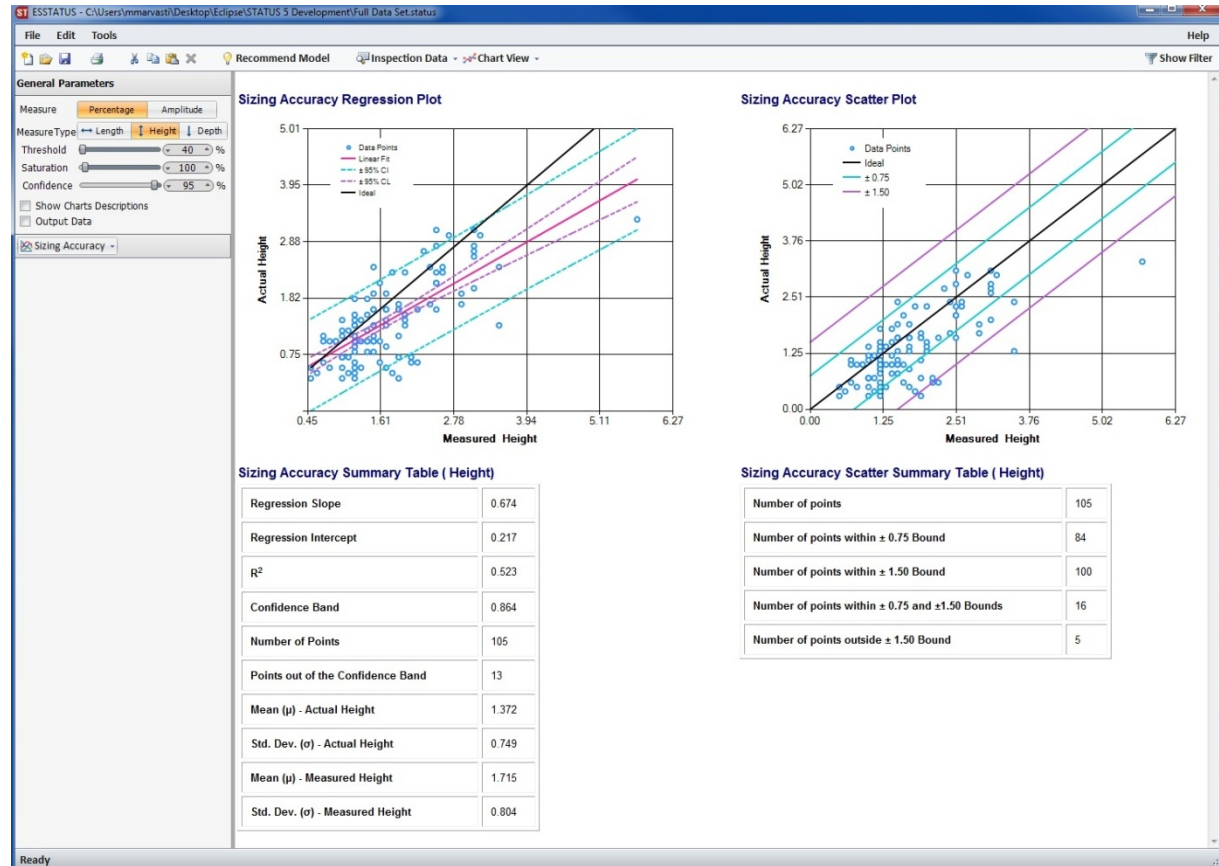
Sizing Assessment Tools

Sizing Accuracy – Sizing Optimization



Sizing Accuracy

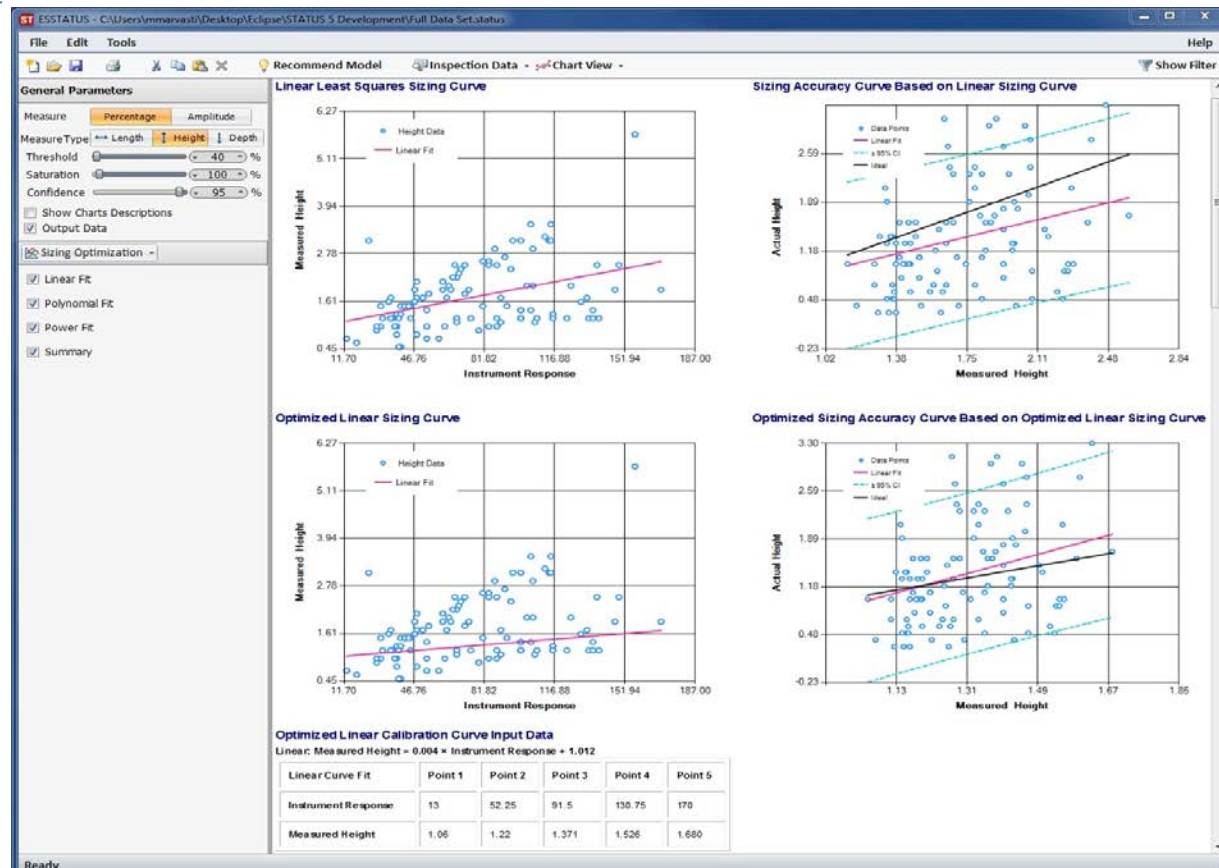
- Measured defect sizes are compared to actual sizes for sizing accuracy assessment.
- Sizing regression fit compares estimated defects sizes with the ideal actual defect size.
- Sizing scatter plots are provided to compare actual defect's sizes to the measured flaw size scatter.
- Sizing regression and scatter plot results are summarized in tables with key information.

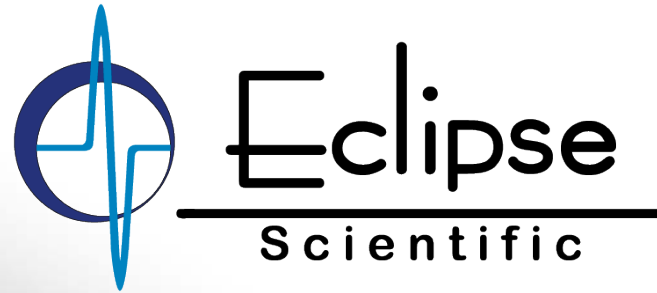




Sizing Optimization

- Recommends the optimum calibration curve fit formula comparing linear, polynomial and power fits.
- Calculates the optimum calibration curve to be used in the instrument for sizing.
- Optimum calibration curve usage results in defect's size measurements match more closely to actual sizes.
- Optimum calibration curve formula and instrument data import table is provided.





www.eclipsescientific.com

